Search Notes			

Application/Control No.	Applicant(s)/Patent und Reexamination	Applicant(s)/Patent under Reexamination	
10/665,732	NAGASE, MAKOTO		
Examiner	Art Unit		
Shih-wen Hsieh	2861		

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Class	Subclass	Date	Examiner
347	22,24,28 29,30,33	6/16/2005	swн
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